

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/594,065 TAKEUCHI ET AL.	
		Examiner	Art Unit VERNON P. WEBB	2811 Page 1 of 1

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*	B	US-2004/0169184 A1	09-2004	Udagawa et al.	257/086
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NON-PATENT DOCUMENTS

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